

**TRIPLE DIFFUSED PLANER TYPE
HIGH VOLTAGE,HIGH SPEED SWITCHING**

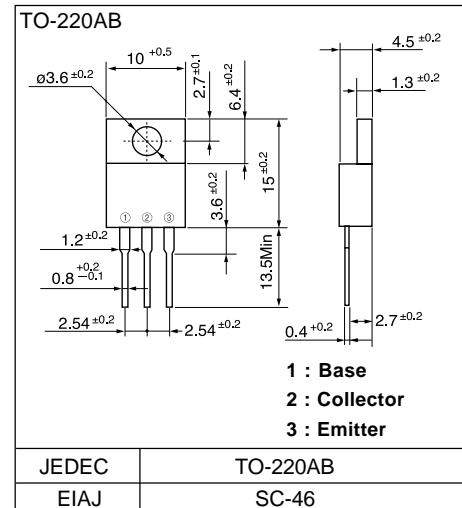
■ Features

- High voltage,High speed switching
- High reliability

■ Applications

- Switching regulators
- Ultrasonic generators
- High frequency inverters
- General purpose power amplifiers

■ Outline Drawings



■ Maximum ratings and characteristics

● Absolute maximum ratings ($T_c=25^\circ\text{C}$ unless otherwise specified)

Item	Symbol	Ratings	Unit
Collector-Base voltage	V_{CBO}	500	V
Collector-Emitter voltage	V_{CEO}	400	V
Collector-Emitter voltage	$V_{CEO}(\text{SUS})$	400	V
Emitter-Base voltage	V_{EBO}	7	V
Collector current	I_C	5	A
Base current	I_B	2	A
Collector power dissipation	P_C	40	W
Operating junction temperature	T_j	+150	$^\circ\text{C}$
Storage temperature	T_{stg}	-65 to +150	$^\circ\text{C}$

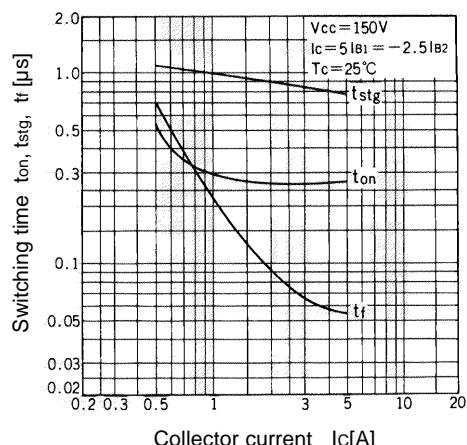
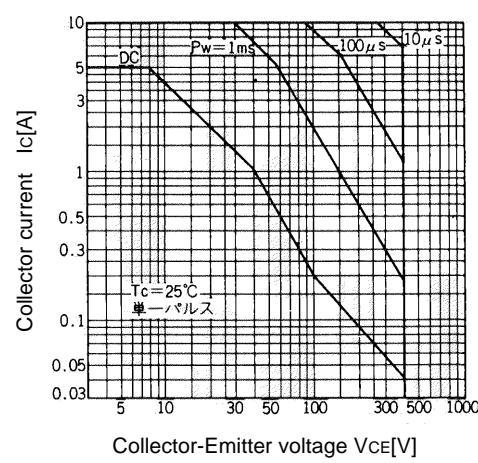
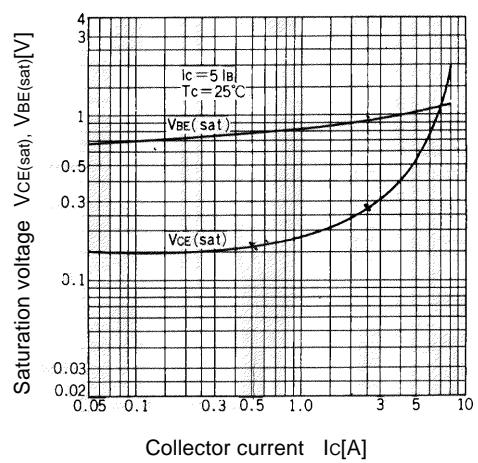
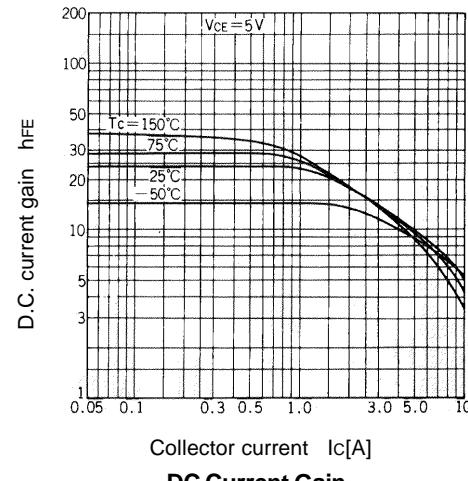
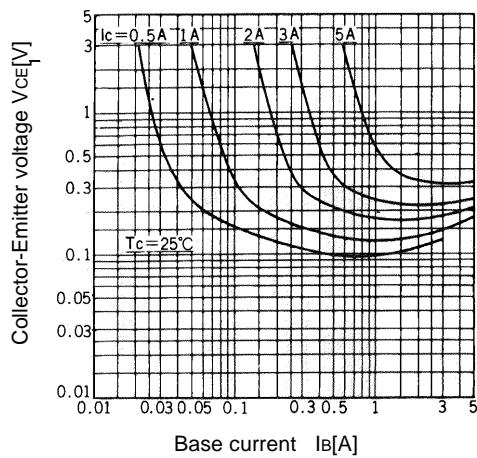
● Electrical characteristics ($T_c = 25^\circ\text{C}$ unless otherwise specified)

Item	Symbol	Test Conditions	Min.	Typ.	Max.	Units
Collector-Base voltage	V_{CBO}	$I_{CBO} = 1\text{mA}$	500			V
Collector-Emitter voltage	V_{CEO}	$I_{CEO} = 10\text{mA}$	400			V
Collector-Emitter voltage	$V_{CEO}(\text{SUS})$	$I_C = 0.2\text{A}$	400	-		V
Emitter-Base voltage	V_{EBO}	$I_{EBO} = 1\text{mA}$	7	-		V
Collector-Base leakage current	I_{CBO}	$V_{CBO} = 500\text{V}$		-	1.0	mA
Emitter-Base leakage current	I_{EBO}	$V_{EBO} = 7\text{V}$		-	1.0	mA
D.C. current gain	h_{FE}	$I_C = 2\text{A}, V_{CE} = 5\text{V}$	10			
Collector-Emitter saturation voltage	$V_{CE}(\text{Sat})$	$I_C = 2\text{A}, I_B = 0.4\text{A}$			1.0	V
Base-Emitter saturation voltage	$V_{BE}(\text{Sat})$				1.5	V
*1	t_{on}	$I_C = 2.5\text{A}, I_B1 = 0.5\text{A}$			0.5	μs
Switching time	t_{stg}	$I_B2 = -1\text{A}, R_L = 60\text{ ohm}$			1.5	μs
	t_f	$P_w = 20\mu\text{s}$ Duty=<2%			0.15	μs

● Thermal characteristics

Item	Symbol	Test Conditions	Min.	Typ.	Max.	Units
Thermal resistance	$R_{th(j-c)}$	Junction to case			3.13	$^\circ\text{C/W}$

■ Characteristics



Switching Time

*1 **Switching Time Test Circuit**

